

**Search Notes**

Application/Control No.

10/002,745

Examiner

Philip J. Chea

Applicant(s)/Patent under  
Reexamination

UENO, TOSHIO

Art Unit

2153

**SEARCHED**

Class	Subclass	Date	Examiner
705	7	12/8/2005	PJC
705	8	12/8/2005	PJC
706	50	12/8/2005	PJC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
consulted Primary (709/200+) Dung Dinh on patentability	12/8/2005	PJC
consulted Primary 705 Romain Jeanty on patentability	12/8/2005	PJC
consulted Michelle Colon (working on related case); provided search terms and reference	12/8/2005	PJC
Google	12/8/2005	PJC
ACM Digital Library (knowledge base, technical support, help desk)	12/8/2005	PJC
citeseer	12/8/2005	PJC